## Integrated Waveguides in Trapped Ion Quantum Computing Chips

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Why Optical Integration in Ion Traps?











Waveguide Simulations



Profile of a slab waveguide with sidewall taper and denoted width and heigth. In the simulation the cladding extends 5  $\mu$ m to all directions.

Finite difference eigenmode simulation of the TEO and TE1 modes. Here the effective index is plotted against the waveguide width at height 150 nm and wavelength 730 nm.

width/nm

700

900

800

1000



TE0, w=500 nm -2 TE1, w=500 nm

ToDo: Fabrication and assembly of final design, trapping of ions Problems: stray light, small bending radii







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Field amplitude of a cut through the waveguide/cladding stack of modes TEO und TE1 at a width of 600 nm. The waveguide is placed in the middle of the image. Here the TE1 is a guided mode in the waveguide.



Field amplitude of modes TE0 und TE1 at a width of 500 nm. The waveguide is placed in the middle of the image. Here the TE1 is not guided in the waveguide. Instead we can see a mode that is guided at the boundaries of the cladding where a reflective metal boundary was placed.



test chip containing waveguide meanders of different lengths for cutback trials to obtain the waveguide losses.

ToDo: Fabrication of test chips, Characterization of materials and waveguides, Process development and optimization, Grating design and fabrication.



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